


IRLML0060TRPbF

Electrical Characteristics @ T_J = 25°C (unless otherwise specified)

	Parameter	Min.	Typ.	Max.	Units	Conditions
V _{(BR)DSS}	Drain-to-Source Breakdown Voltage	60	—	—	V	V _{GS} = 0V, I _D = 250μA
ΔV _{(BR)DSS} /ΔT _J	Breakdown Voltage Temp. Coefficient	—	0.06	—	V/°C	Reference to 25°C, I _D = 1mA
R _{DS(on)}	Static Drain-to-Source On-Resistance	—	98	116	mΩ	V _{GS} = 4.5V, I _D = 2.2A
		—	78	92		V _{GS} = 10V, I _D = 2.7A
V _{GS(th)}	Gate Threshold Voltage	1.0	—	2.5	V	V _{DS} = V _{GS} , I _D = 25μA
I _{DSS}	Drain-to-Source Leakage Current	—	—	20	μA	V _{DS} = 60V, V _{GS} = 0V
		—	—	250		V _{DS} = 60V, V _{GS} = 0V, T _J = 125°C
I _{GSS}	Gate-to-Source Forward Leakage	—	—	100	nA	V _{GS} = 16V
	Gate-to-Source Reverse Leakage	—	—	-100		V _{GS} = -16V
R _G	Internal Gate Resistance	—	1.6	—	Ω	
g _{fs}	Forward Trans conductance	7.6	—	—	S	V _{DS} = 25V, I _D = 2.7A
Q _g	Total Gate Charge	—	2.5	—	nC	I _D = 2.7A
Q _{gs}	Gate-to-Source Charge	—	0.7	—		V _{DS} = 30V
Q _{gd}	Gate-to-Drain ('Miller') Charge	—	1.3	—		V _{GS} = 4.5V ②
t _{d(on)}	Turn-On Delay Time	—	5.4	—	ns	V _{DD} = 30V ②
t _r	Rise Time	—	6.3	—		I _D = 1.0A
t _{d(off)}	Turn-Off Delay Time	—	6.8	—		R _G = 6.8Ω
t _f	Fall Time	—	4.2	—		V _{GS} = 4.5V
C _{iss}	Input Capacitance	—	290	—	pF	V _{GS} = 0V
C _{oss}	Output Capacitance	—	37	—		V _{DS} = 25V
C _{rss}	Reverse Transfer Capacitance	—	21	—		f = 1.0MHz

Source-Drain Ratings and Characteristics

	Parameter	Min.	Typ.	Max.	Units	Conditions
I _S	Continuous Source Current (Body Diode)	—	—	1.6	A	MOSFET symbol showing the integral reverse p-n junction diode. 
I _{SM}	Pulsed Source Current (Body Diode) ①	—	—	11		
V _{SD}	Diode Forward Voltage	—	—	1.3	V	T _J = 25°C, I _S = 2.7A, V _{GS} = 0V ②
t _{rr}	Reverse Recovery Time	—	14	21	ns	T _J = 25°C, V _R = 30V, I _F = 1.6A
Q _{rr}	Reverse Recovery Charge	—	13	20	nC	di/dt = 100A/μs ②

Notes:

- ① Repetitive rating; pulse width limited by max. junction temperature.
- ② Pulse width ≤ 400μs; duty cycle ≤ 2%.
- ③ Surface mounted on 1 in square Cu board

IRLML0060TRPbF

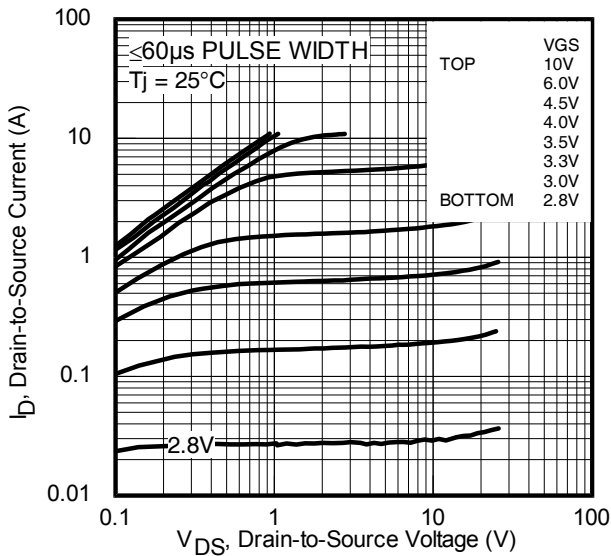


Fig. 1 Typical Output Characteristics

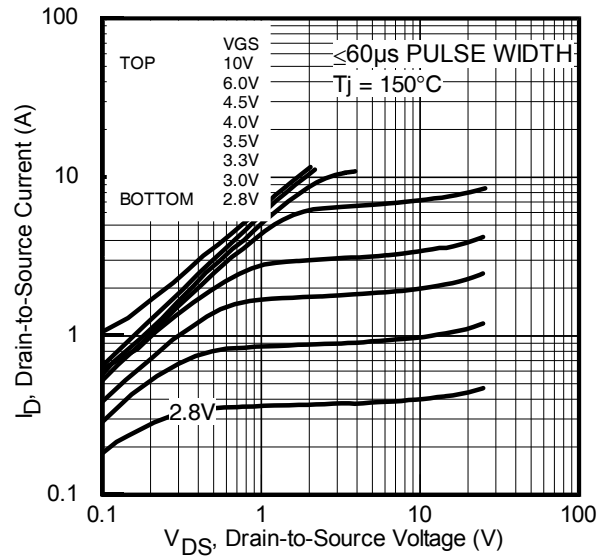


Fig. 2 Typical Output Characteristics

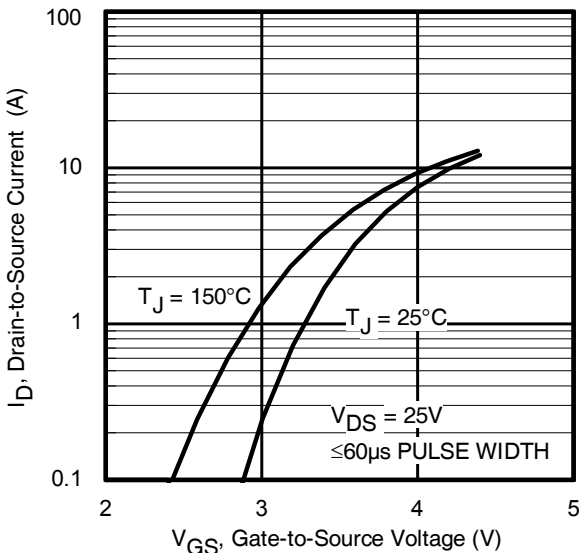


Fig. 3 Typical Transfer Characteristics

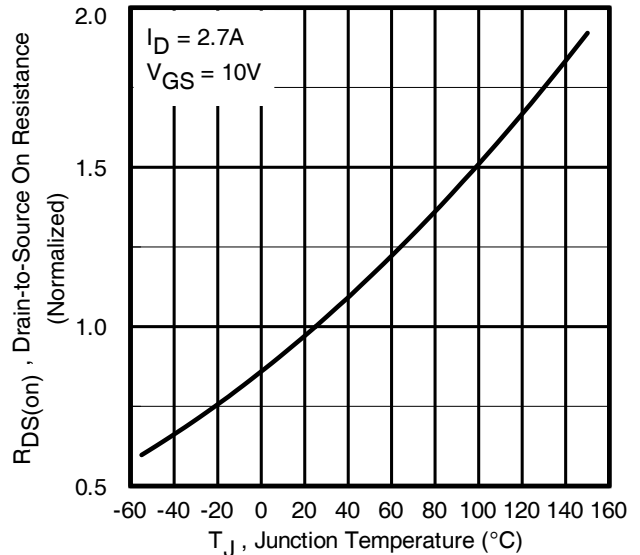


Fig. 4 Normalized On-Resistance vs. Temperature

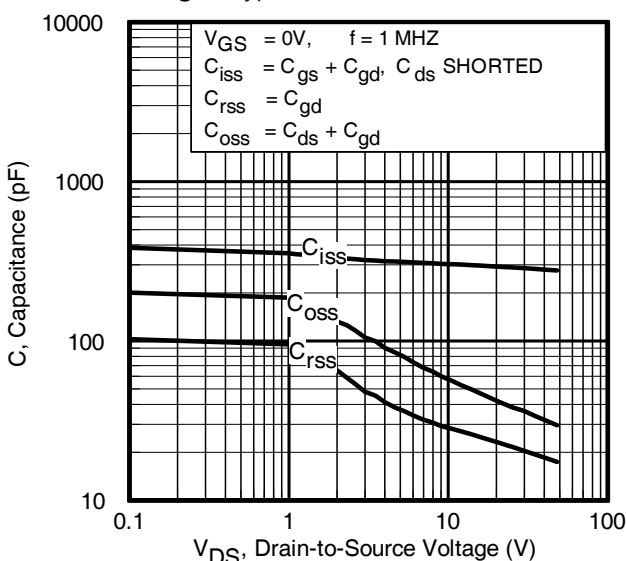


Fig. 5. Typical Capacitance vs. Drain-to-Source Voltage

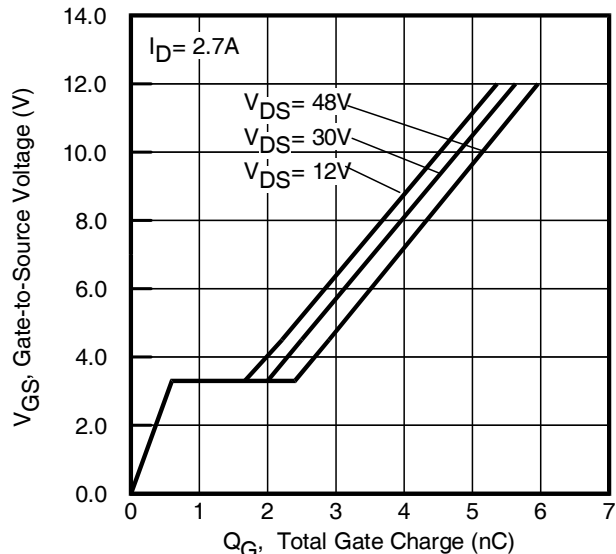


Fig 6. Typical Gate Charge vs. Gate-to-Source Voltage

IRLML0060TRPbF

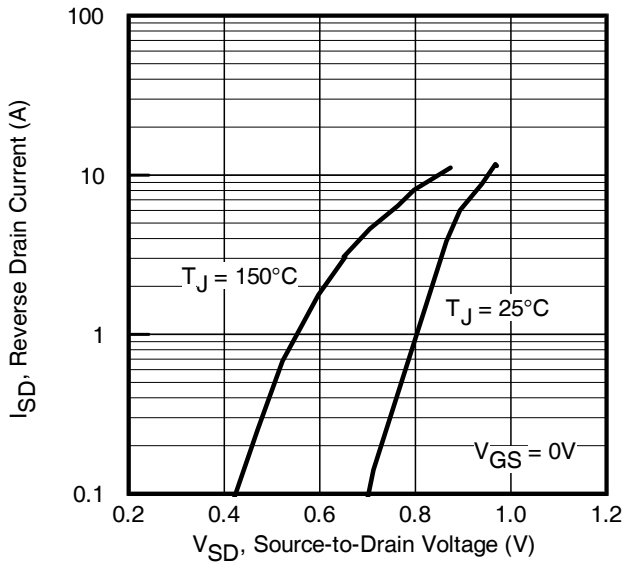


Fig. 7 Typical Source-to-Drain Diode Forward Voltage

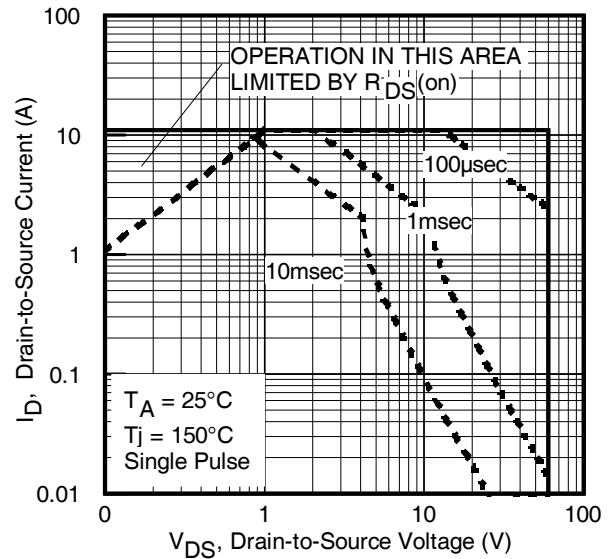


Fig 8. Maximum Safe Operating Area

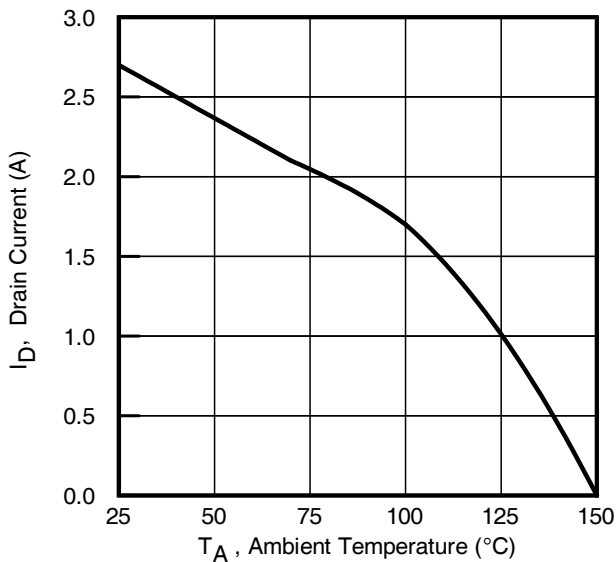


Fig 9. Maximum Drain Current vs. Case Temperature

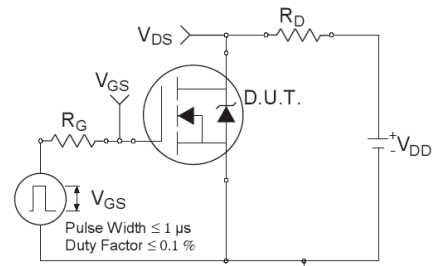


Fig 10a. Switching Time Test Circuit

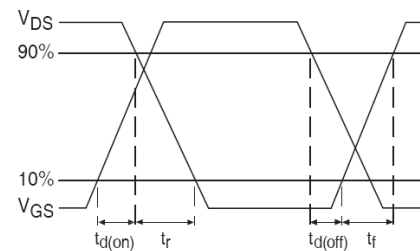


Fig 10b. Switching Time Waveforms

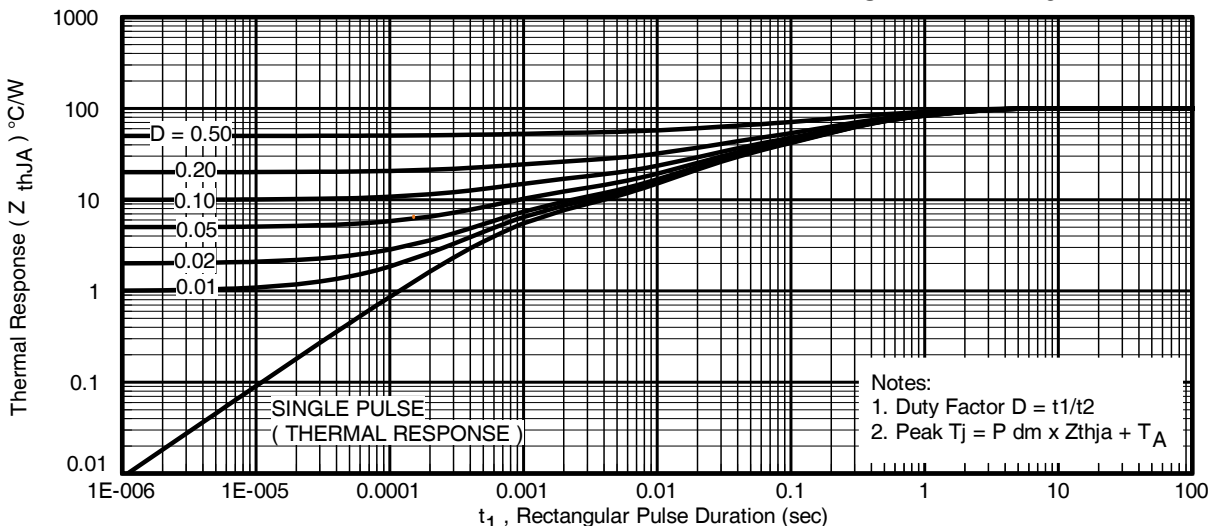


Fig 11. Maximum Effective Transient Thermal Impedance, Junction-to-Ambient

IRLML0060TRPbF

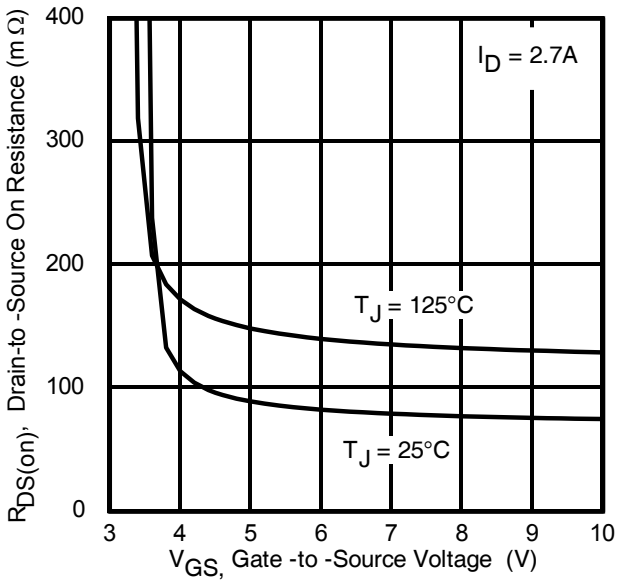


Fig 12. Typical On-Resistance Vs. Gate Voltage

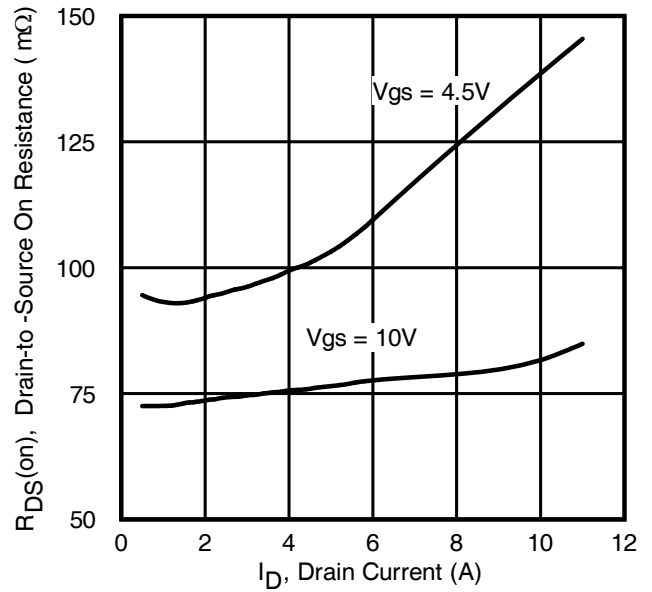


Fig 13. Typical On-Resistance Vs. Drain Current

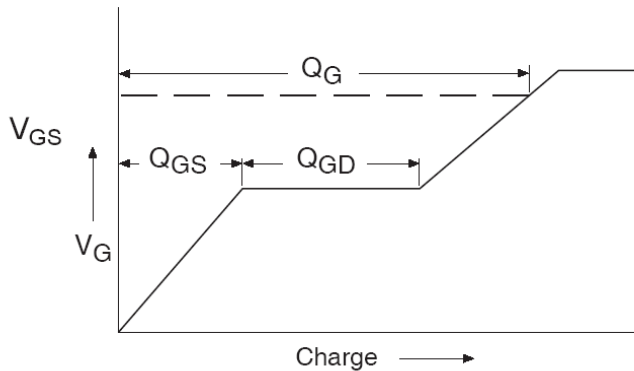


Fig 14a. Basic Gate Charge Waveform

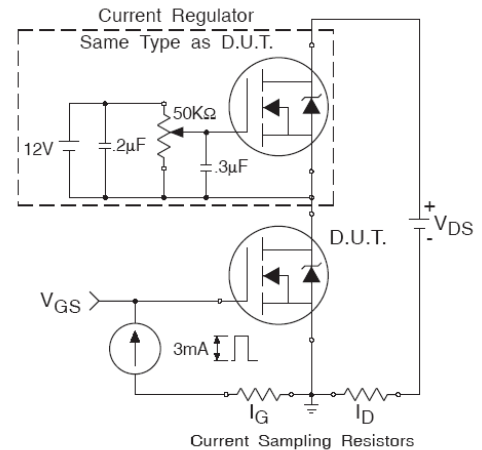


Fig 14b. Gate Charge Test Circuit

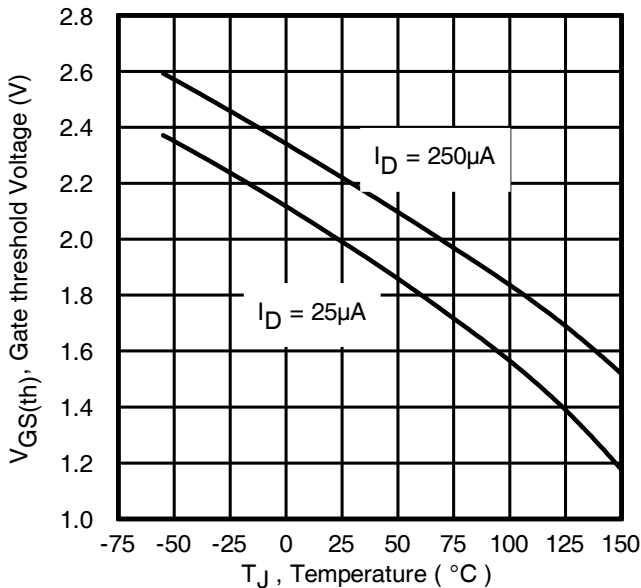


Fig 15. Typical Threshold Voltage Vs. Junction Temperature

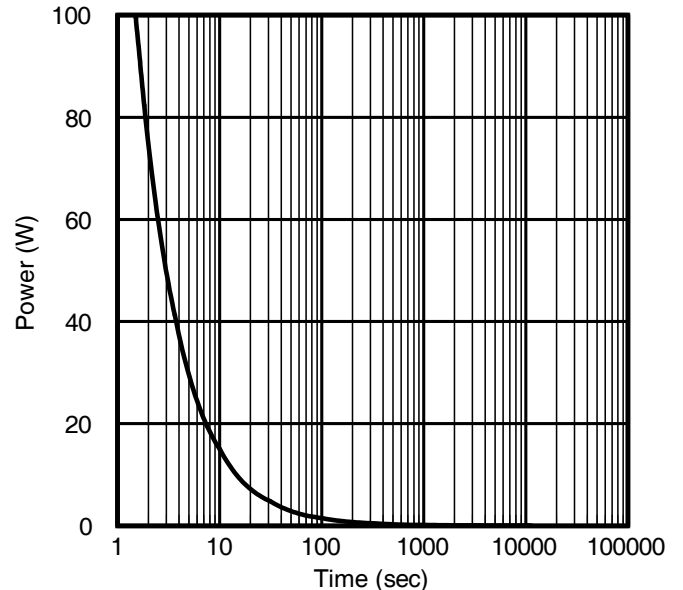


Fig 16. Typical Power Vs. Time